Title: Holistic approach to DFT: Component to System

As the complexities of semiconductor chip and PCB design complexities are increases, testing of components to systems, quintessential need for a quality manufacturing test is becoming a challenge. This makes it essential to have a good ‘Design for Test’ (DFT) from a component to a system to ensure a robust structural test all through.

§ What are the benefits of adding DFT elements?

§ What are the aspects to be considered for enhancing ‘DFT’?

§ What is the value across the Product Life Cycle - chip to system?

§ How can the DFT be best leveraged across phases of Product Life Cycle?

By answering the above questions, we will conclude on how a holistic approach to DFT can enhance testability and quality from a chip to a system.